

Notice of References Cited

Application/Control No.

09/738,650

Applicant(s)/Patent Under
Reexamination
COHEN-SOLAL, ERIC

Examiner

BRIAN P. YENKE

Art Unit

2614

Page 1 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,541,662	07-1996	Adams et al.	348/460
	B	US-			
	C	US-6,473,130	10-2002	Kim, Seung-Man	348/565
	D	US-6,473,102	10-2002	Rodden et al.	345/788
	E	US-2002/0070957	06-2002	Trajkovic et al.	345/719
	F	US-6,320,623	11-2001	Cavallerano et al.	348/553
	G	US-6,088,064	07-2000	Rumreich et al.	348/564
	H	US-6,311,328	10-2001	Miyazaki et al.	725/37
	I	US-6,556,253	04-2003	Megied et al.	348/565
	J	US-6,359,657	03-2002	Westerink et al.	348/584
	K	US-6,542,621	04-2003	Brill et al.	382/103
	L	US-2002/0069411	06-2002	Rainville et al.	725/37
	M	US-4,367,484	01-1983	Kuroyanagi et al.	348/566

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

09/738,650

Applicant(s)/Patent Under
Reexamination
COHEN-SOLAL, ERIC

Examiner

BRIAN P. YENKE

Art Unit

2614

Page 2 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,353,450	03-2002	DeLeeuw, William C.	345/768
	B	US-6,108,042	08-2000	Adams et al.	348/460
	C	US-5,760,838	06-1998	Adams et al.	348/460
	D	US-2003/0016304	01-2003	NORSWORTHY et al.	348/565
	E	US-2001/0040584	11-2001	DELEEUEW, WILLIAM C.	345/629
	F	US-6,556,252	04-2003	Kim, Dae Joong	348/565
	G	US-6,493,038	12-2002	Singh et al.	348/565
	H	US-6,493,036	12-2002	Fernandez, Gustavo A.	348/561
	I	US-6,357,045	03-2002	Devaney, Patrick W.	725/138
	J	US-5,398,074	03-1995	Duffield et al.	348/564
	K	US-5,206,714	04-1993	Kim, Yong-Je	348/565
	L	US-6,201,879	03-2001	Bender et al.	382/100
	M	US-6,052,155	04-2000	Cherrick et al.	348/565

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

09/738,650

Applicant(s)/Patent Under
Reexamination
COHEN-SOLAL, ERIC

Examiner

BRIAN P. YENKE

Art Unit

2614

Page 3 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,008,860	12-1999	Patton et al.	348/565
	B	US-5,610,664	03-1997	Bobert, Martin	348/564
	C	US-5,589,893	12-1996	Gaughan et al.	725/37
	D	US-5,574,507	11-1996	Baek, Woon G.	348/511
	E	US-5,047,857	09-1991	Duffield et al.	348/553
	F	US-2002/0140861	10-2002	Janevski et al.	348/565
	G	US-2002/0140862	10-2002	Dimitrova et al.	348/565
	H	US-4,574,364	03-1986	Tabata et al.	345/798
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.